Editorial

The second meeting of the CFMCP was held in July 94 at the Ecole Nationale Supérieure des Arts et Métiers d'Aix-en-Provence. The aim of this three days meeting was to gather a large number of french scientists interested in the field of near-field microscopies of different kinds and using scanning probe methods. This was an opportunity for them to appreciate the progress in this domain and its applications.

More than 130 participants attended the conference and proposed numerous oral and poster contributions on various research areas. This, as well as the quality of the contributions, is a good proof of the enthusiasm of this young community and of the standard know-how acquired in the field.

In order to have a general overview of the possibilities offered in the field, the first sessions were animated by international speakers invited for their outstanding contributions. H. ROHRER thus introduced this meeting by a general talk on the chances and challenges in nanoscience and nanotechnology. D. VAN LABEKE reported on the recent progress in near-field optical microscopy. The mastery acquired in probing biological samples using AFM was commented and illustrated by H. GAUB. Recent developments on real time imaging at high temperatures were also illustrated by a video film on high temperature growth of Si and commented by U. KOEHLER. Finally, R. MORIN presented a talk on point source physics with applications to projection microscopy and electron holography.

These stimulating introductory lectures were followed by a dense program on numerous applications in the following fields: biology, near-field optical microscopy, soft and organic materials, new developments towards quantitative microscopy, image processing, instrumentation, physicochemistry of surfaces using UHV-STM or electrochemistry. On the whole, 70 contributions, oral or poster, were presented.

The presence of exhibition booths allowed contacts with professionals from important instrumentation companies.

The following proceedings with 30 invited or contributed papers testify of the importance and the quality of this meeting. The editors wish to thank the participants for their diligent presence at all sessions despite of the torrid atmosphere of these three days, and they hope to meet them at the next CFMCP meeting.

The CFMCP network can be contacted by e-mail at the following address: cfmcp-ad@gpec.univ-mrs.fr. The editors wish to collect all the e-mail addresses. So, we suggest to all the CFMCP members to use this network for sending their coordinates, as well as comments on new activities and developments of our program.

Louis Porte

Ecole Centrale de Lyon
Ecully

Frank Salvan

Groupe de Physique
des Etats Condensés
Luminy